

CAD Reference Flow for 3D Via-Last Integrated Circuits

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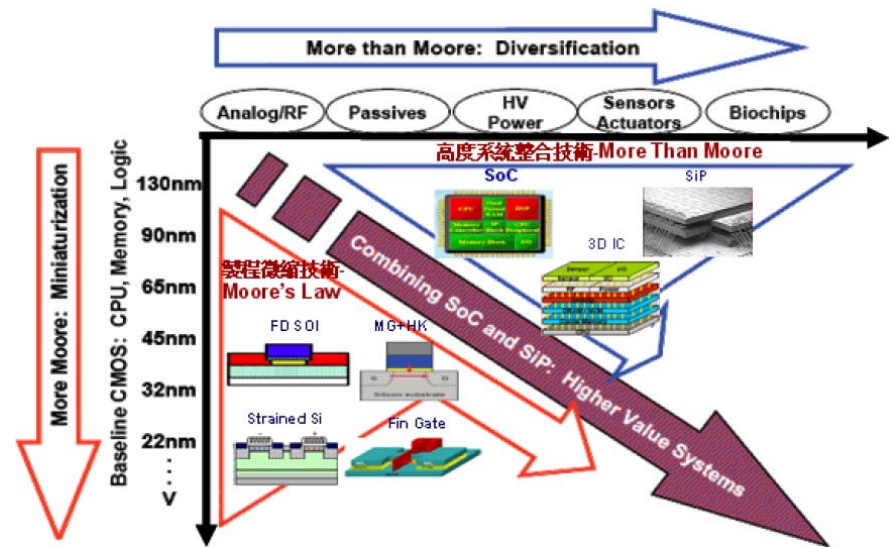
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Outline

- Introduction to 3D Integration
- 3D CAD Reference Flow in ITRI
- Conclusions

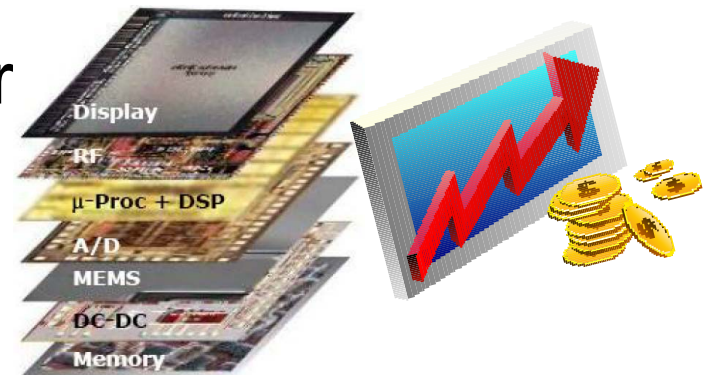
Motivation for 3D Integration

- Challenges below 22 nm
 - Process Variation
 - New materials = \$\$\$
 - Advanced Lithography
 - Extreme UV, or E-beam
 - Both = \$\$\$

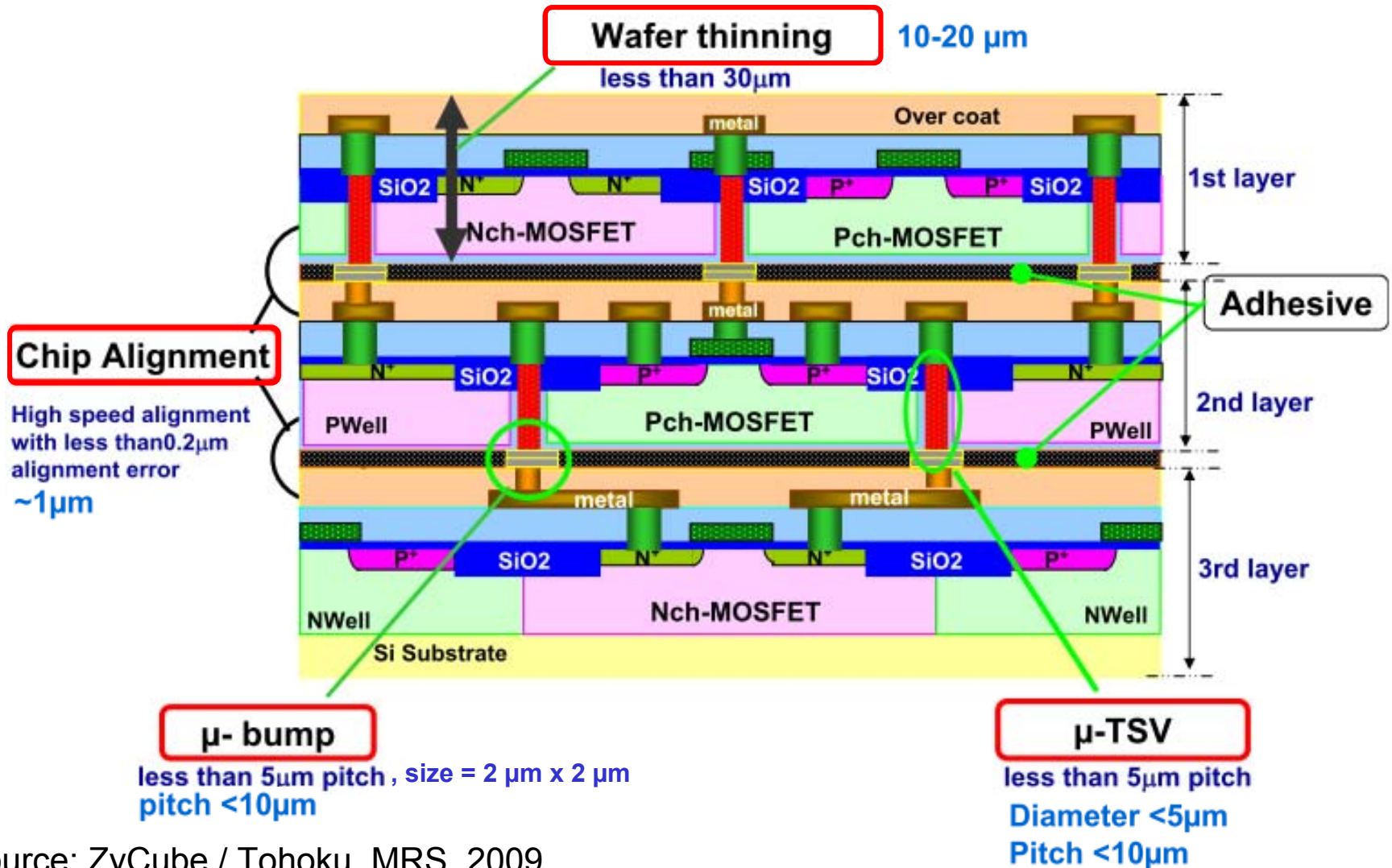


Source: ITRS, 2007

- Thin/Small, Multi-function
- High performance, Low power
- Heterogeneous integration
- ...



Keys of 3D Integration



Source: ZyCube / Tohoku, MRS, 2009

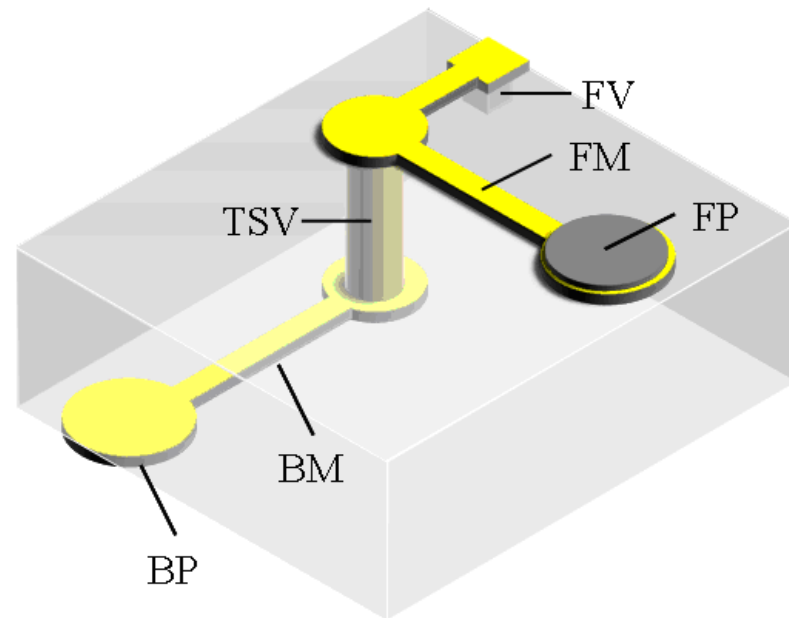
Source: Leti (Fr), D43D, 2009 15th ASP-DAC, Jan. 20, 2010

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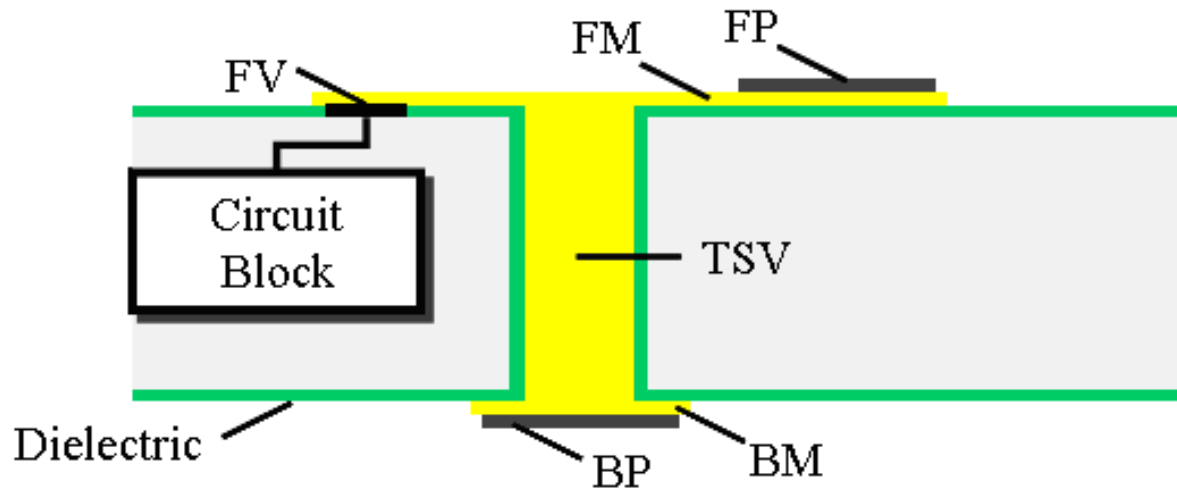
TSV-Related Terminologies

- Through silicon via (TSV)
- Front metal (FM)
- Front via (FV)
- Front pad (FP)
- Back metal (BM)
- Back pad (BP)



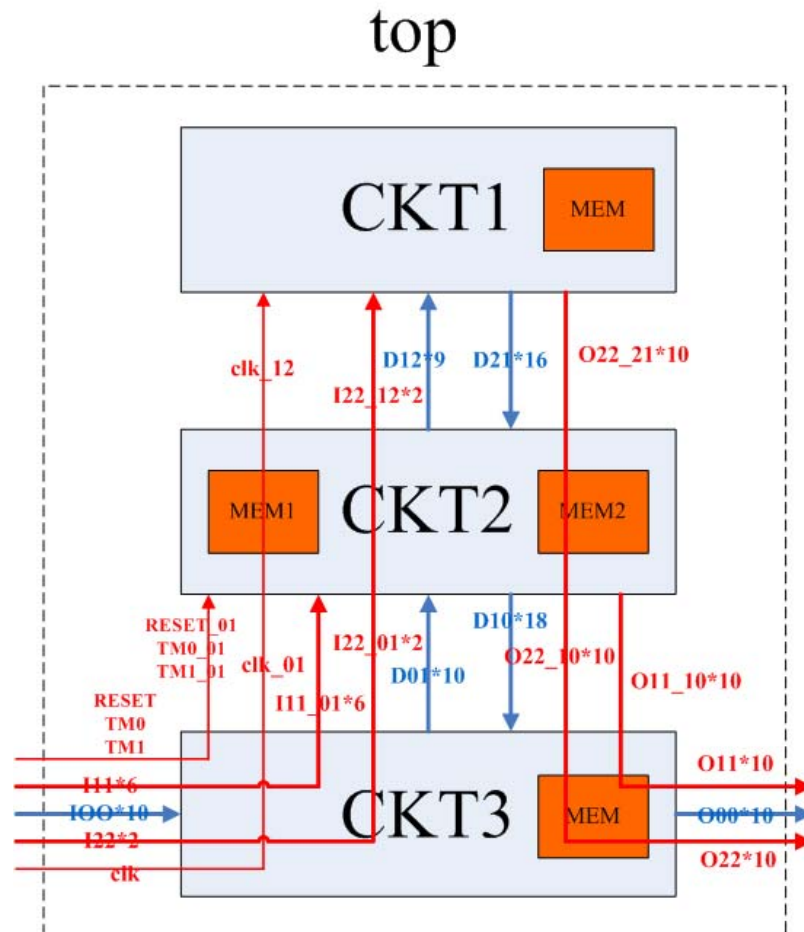
ITRI Integration Approach

- Treat each TSV as a cell through silicon to FM
- Scalable face-to-back bonding
- Align BP with TSV to eliminate BP placement

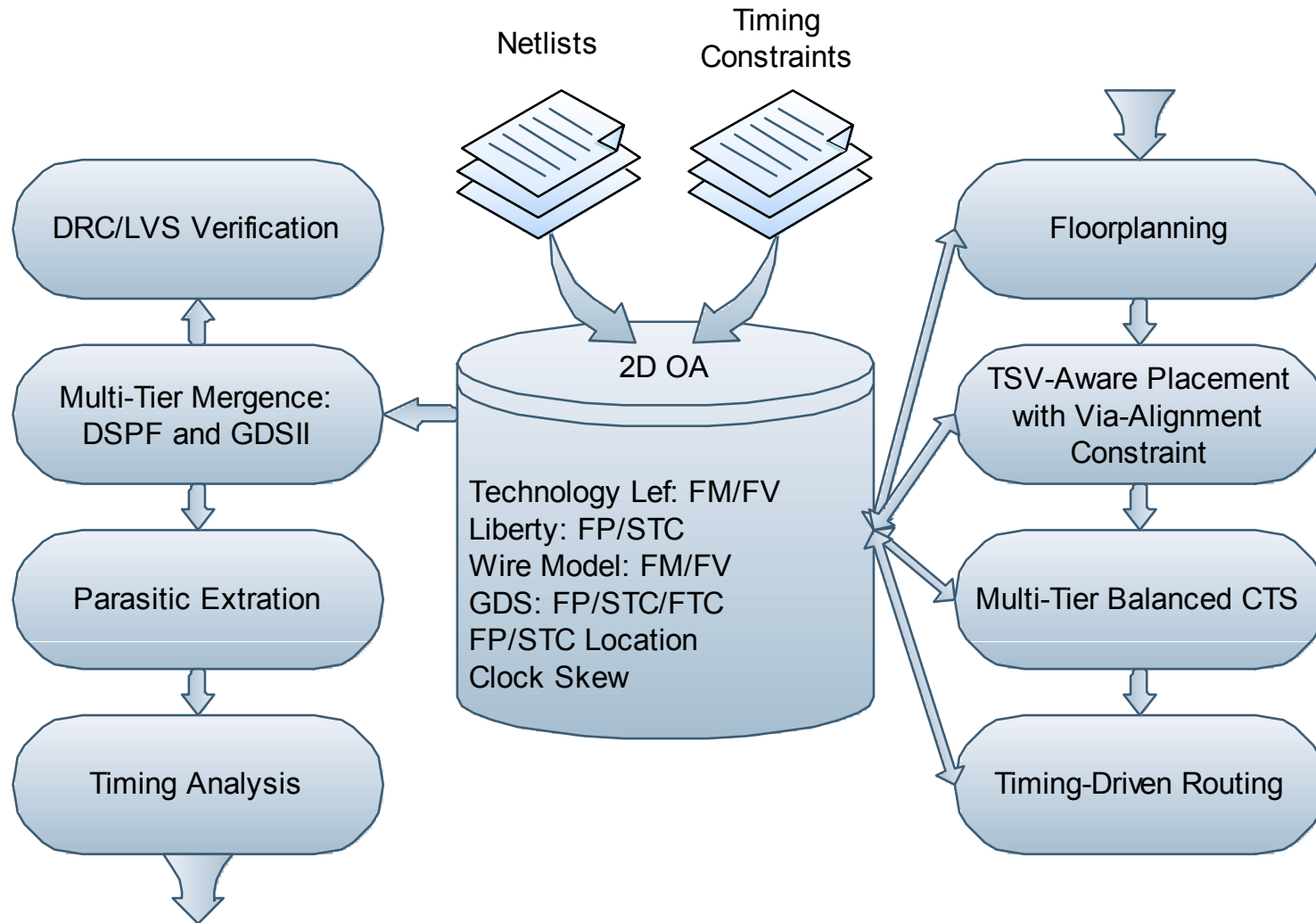


Layer Partition

- TSMC 90nm-G process with TSV and FP cells

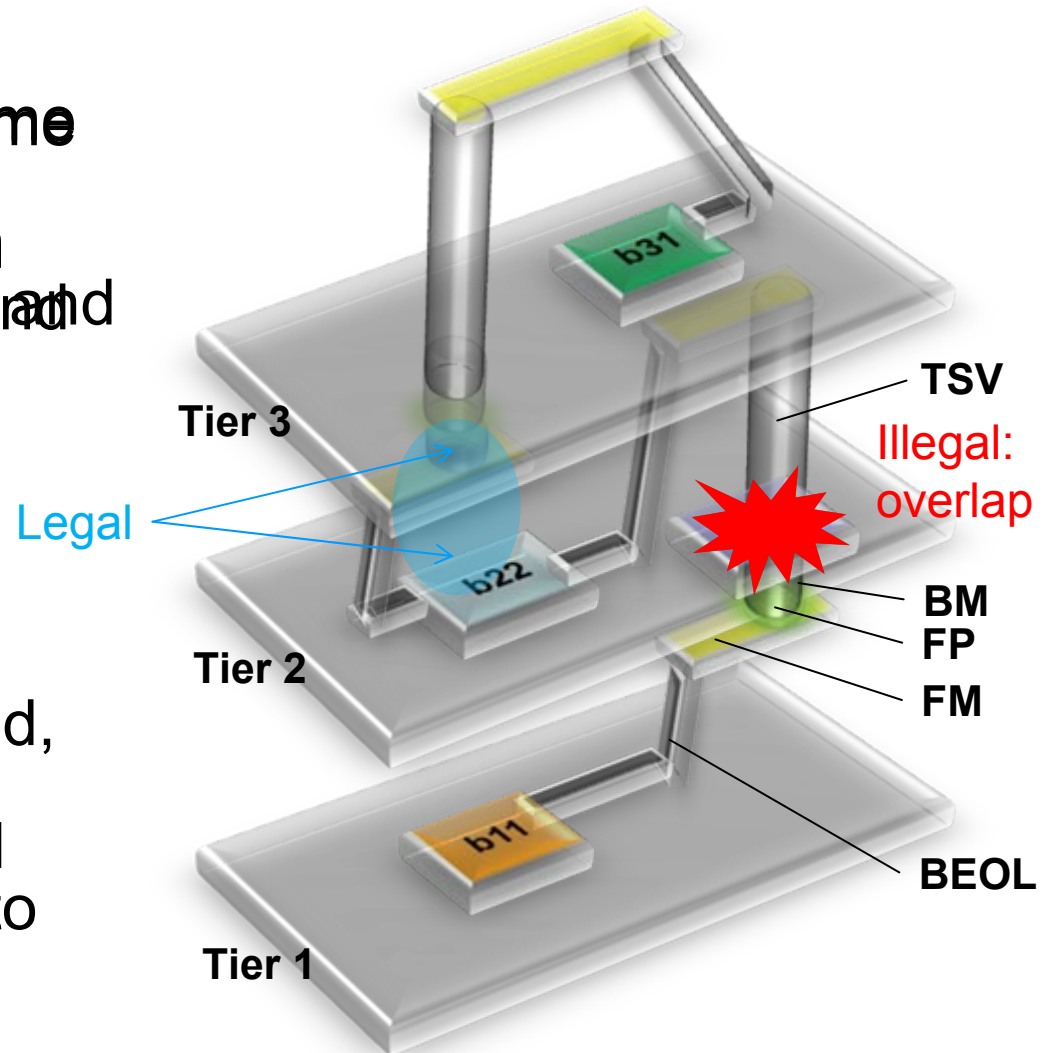


Multi-Tier P&R Methodology

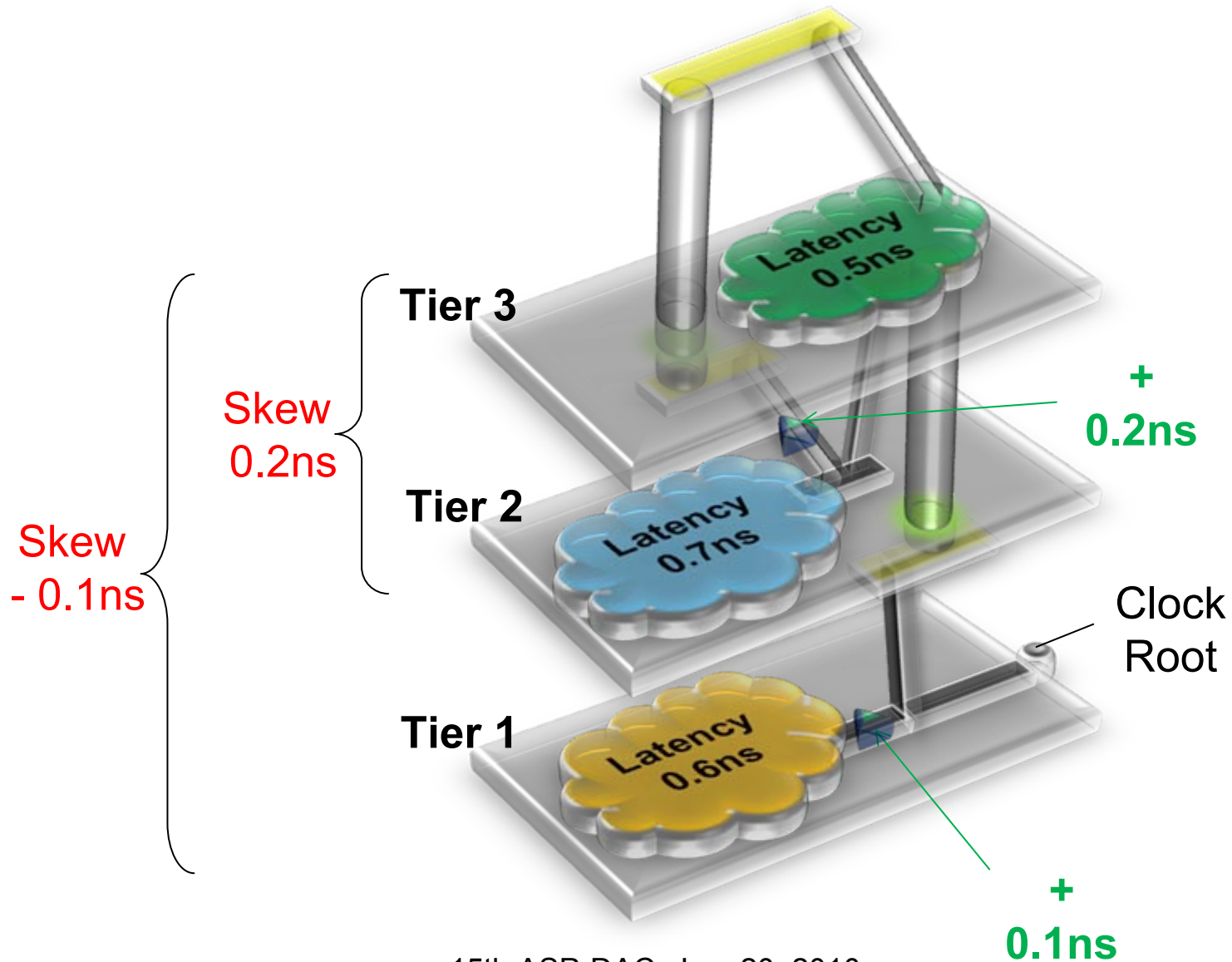


TSV-aware Placement with Via-alignment Constraints

- **Property 2:** On the same tier, any cell and block, except for the FP, can overlap with the STC, and any metal line can be routed over.
- **Theorem 1:** The alignment constraints can always be satisfied, if the placement of FP and STC is performed from the topmost tier to the bottommost tier.

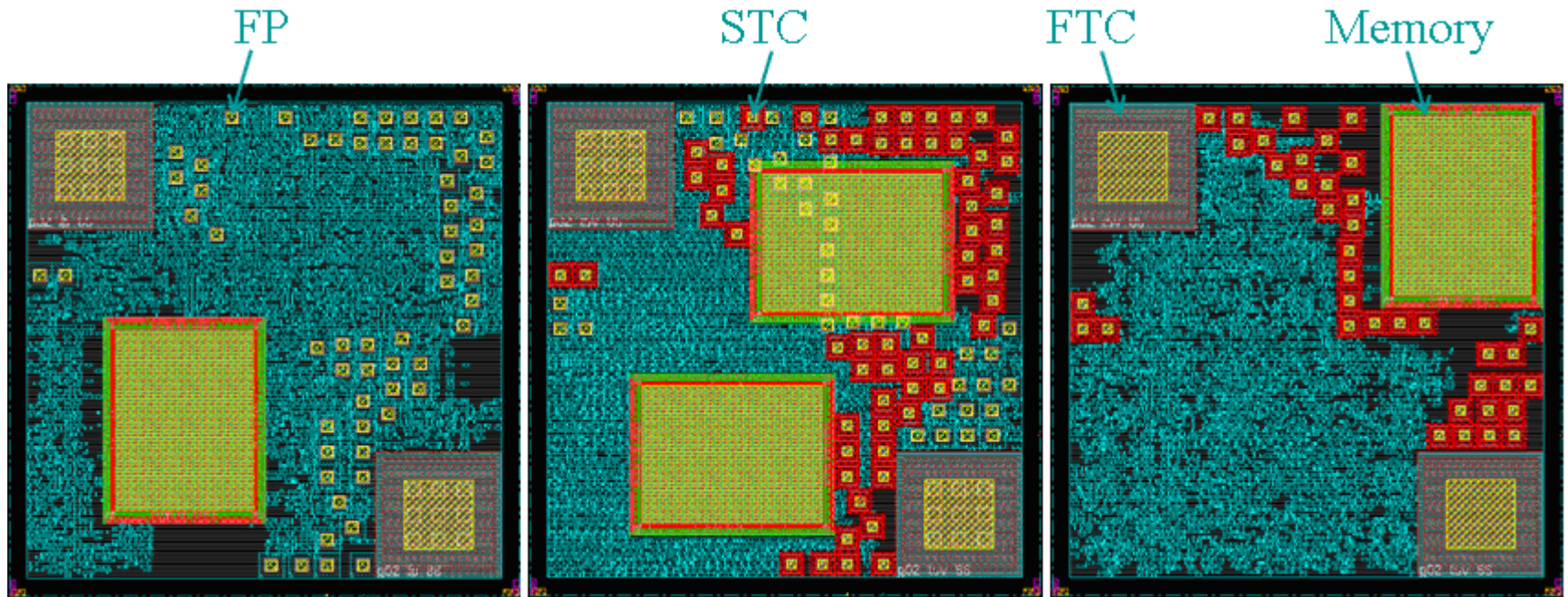


Multi-Tier Balanced CTS



3-Tier Case with Power TSV

- Support 2 kinds of TSV diameters
 - 5um Signal , 50um Power/Ground



(a) Bottom Tier

(b) Middle Tier

(c) Top Tier

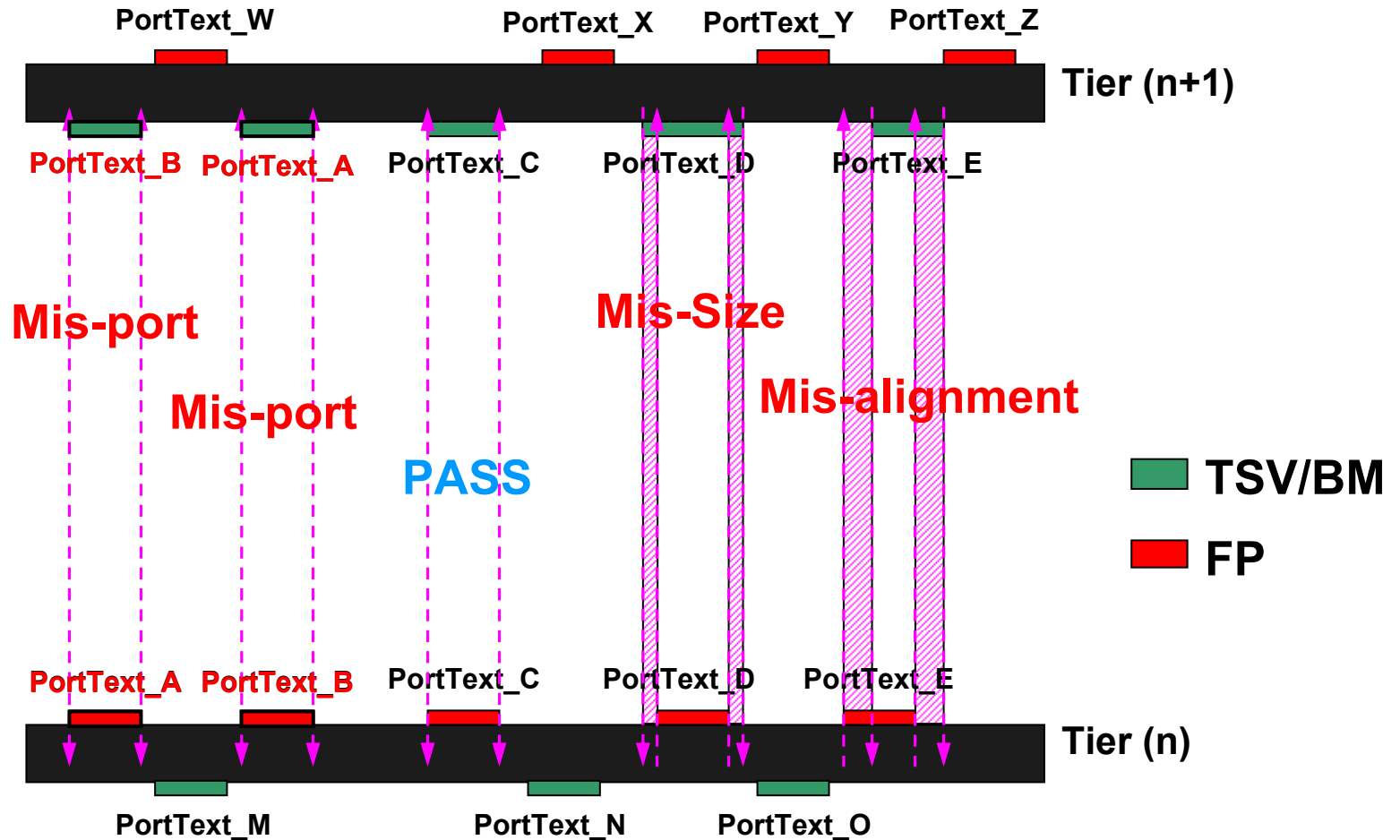
Clock Tree Synthesis Results

		CTS			Multi-Tier Balanced CTS			Δ Skew
Unit: ns	Tier	Max Latency	Min Latency	Inter-Tier Skew	Max Latency	Min Latency	Inter-Tier Skew	
2 Tiers	2	0.252	0.252	0.296	0.252	0.252	0.008	-0.288
	1	0.111	0.104		0.351	0.344		
3 Tiers	3	0.401	0.386	0.608	0.369	0.35	0.05	-0.558
	2	0.395	0.381		0.545	0.531		
	1	0.323	0.298		0.68	0.657		
4 Tiers	4	0.635	0.624	1.546	0.627	0.614	0.245	-1.301
	3	0.54	0.518		0.999	0.985		
	2	0.651	0.625		1.343	1.314		
	1	0.268	0.256		1.282	1.27		

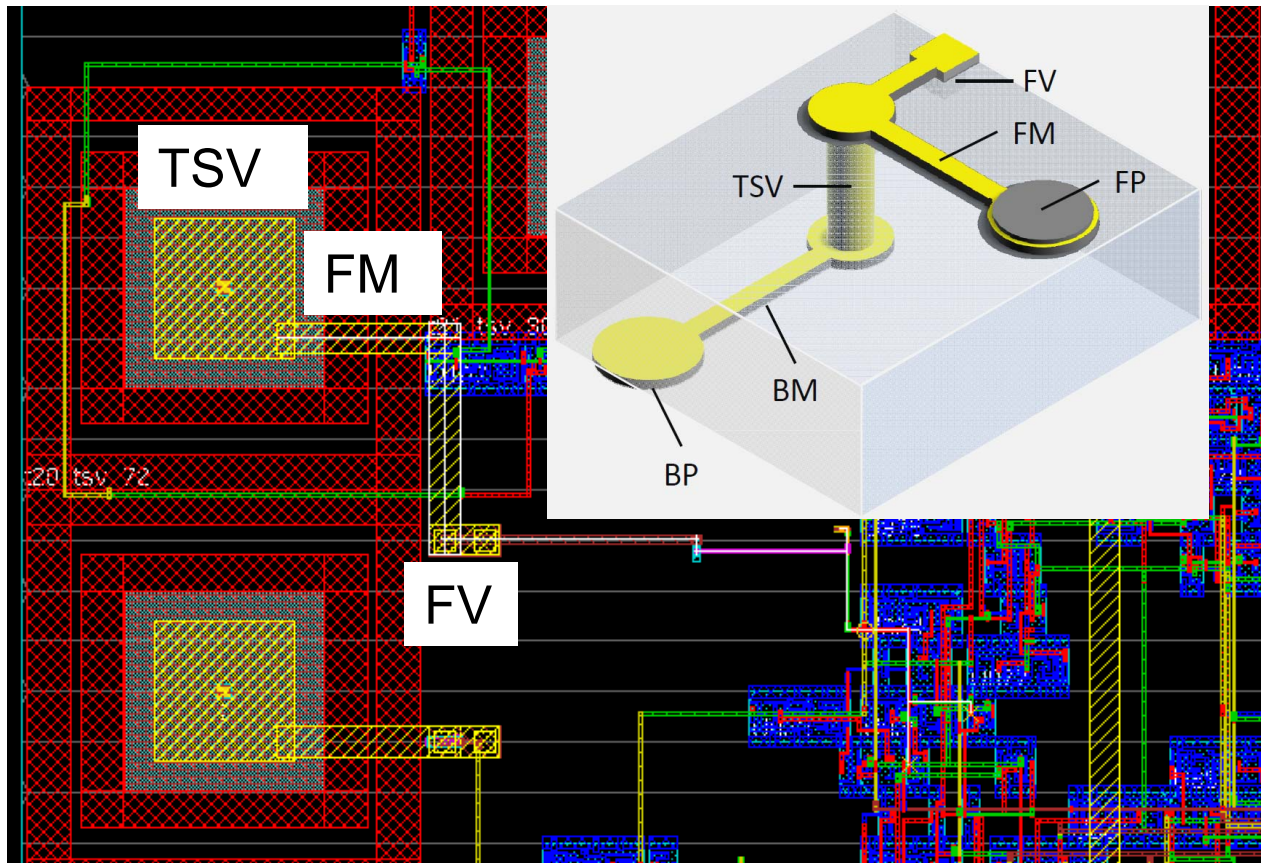
Routing – DRC/LVS

- Design rules are provided for the five extra mask layers
- 3D LVS need to evolve to tackle the vertical interconnect issues across tiers

Different LVS Checking Types



BEOL & FM Routing



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Conclusions

- Multi-Tier P&R Methodology
 - TSV co-placement
 - Via alignment constraints
 - Balanced CTS
 - DRC/LVS

- Future works on 3D Integration
 - Thermal
 - Mechanical

THANKS FOR YOUR ATTENTION

謝謝您的聆聽

